Notice of R ferenc s Cited 09/911,033 LACKRITZ E Examiner Art Unit Kaj Olsen 1753

Applicant(s)/Patent Under Reexamination LACKRITZ ET AL.

Page 1 of 1

U.S. PATENT DOCUMENTS

Application/Control No.

				U.S. PATENT DOCUMENTO	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0029968	03-2002	Tan et al.	204/454
	В	US-2002/0092767	07-2002	Bjornson et al.	204/451
	С	US-6,010,608	01-2000	Ramsey, J. Michael	204/453
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	Ļ	US-			
	М	US-		TOTAL DATENT DOCUMENTS	

FOREIGN PATENT DOCUMENTS

ONLIGHT							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N	WO 98/27423	06-1998	WIPO	Buchmeiser et al.		
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	Q						
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	Т						
I	L						

NON-PATENT DOCUMENTS

		NON-PATENT DOCUMENTS
*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
,	υ	Kameoka et al, Analytical Chemistry, 73(9), pp. 1935-1941, 2001.
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.